Supplementary Materials

Direct Transformation of Crystalline MoO₃ into Few-Layers MoS₂

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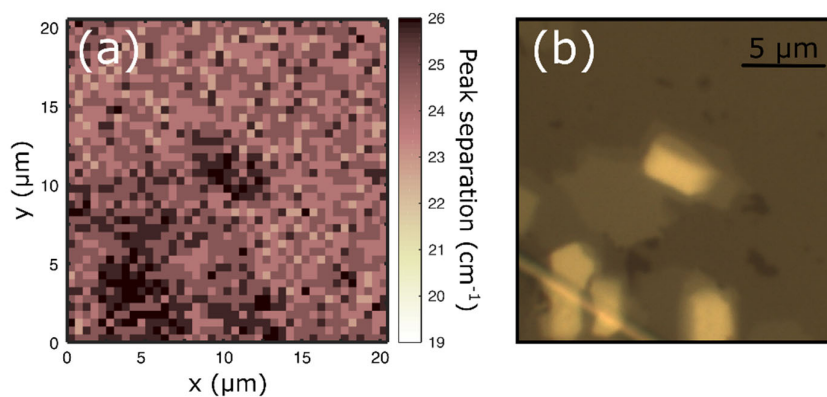
Figure S1. (**a**) Raman map showing the difference between the E^1_{2g} and A_{1g} peaks. The map shows a large region of ~4 layers, according to the peak difference value, and a thicker region in the bottom left corner. (**b**) Optical image of the same region studied in (**a**).
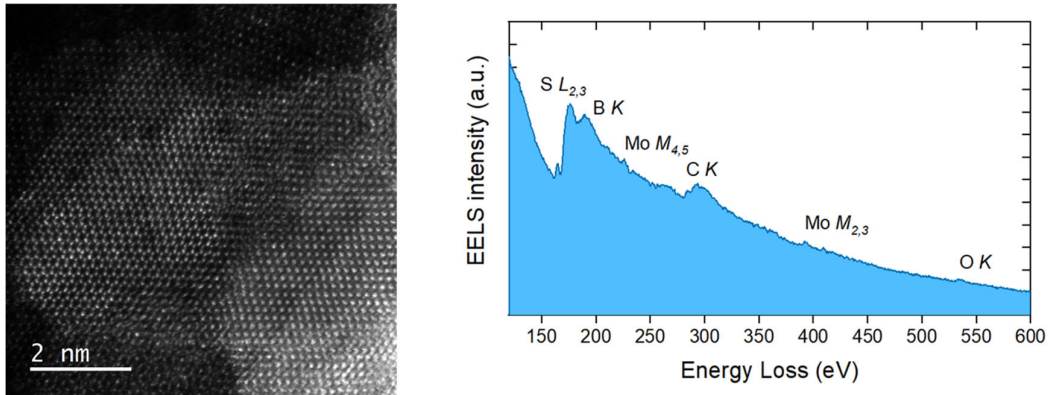
Figure 2. (**a**) High magnification HAADF image of a MoS$_2$ thin film transferred over a holey Si$_3$N$_4$ membrane support. (**b**) Electron energy loss spectra (EELS) acquired while scanning over the area in (**a**) for a total time of 20 s.